

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/618,552	YAKURA ET AL.
	Examiner Shih-wen Hsieh	Art Unit 2861

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
347	29,23	5/4/2005	SWH
347	30,33	5/4/2005	SWH
347	35	5/4/2005	SWH